Fast and Accurate Film Thickness Measurement Advanced Fiber Optic Spectrometer with 83% Quantum Efficiency at 232nm

Basic Information

Place of Origin: CHINA
Brand Name: JINSP
Certification: ISO9001
Model Number: SR100Q
Minimum Order Quantity: 1

• Price: Negotiable

Packaging Details: International Shipping Pakcage

Delivery Time: 90-120 working days
 Payment Terms: T/T, Western Union
 Supply Ability: 100PCS/90-120 days



Product Specification

Spectrual Range: 200nm - 1100nmEffective Pixels: 1024*122

• Qutuam Efficiency: QE92%peak@650nm, 83%@232nm

• SNR: 1000:1

• Highlight: 232nm Fiber Optic Spectrometer



More Images



92% High Quantum Spectrometer for Film Thickness Measurement

With applications spanning electronics, renewables, and optics, thin film technology relies heavily on precise thickness evaluation for surface analysis. Photoelectric measurement solutions stand out for being contact-free, damage-proof, and fast. The integration of intelligent computing with optical systems enhances film quality control, supporting manufacturing upgrades and technological progress.

Product Parameters:

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Detector	Chip Type	Back-illuminated TE-cooled Hamamatsu S7031	
	Effective Pixel	1024*122	
	Pixel Size	24*24μm	
	Sensing Area	24.576*2.928mm	
Optical Parameters	Optical Design	F/4 cross-type	
	Numerical Aperture	0.13	
	Focal Length	100mm	
	Entrance Slit Width	10μm,25μm,50μm,100μm,200μm (customizable)	
	Fiber Interface	SMA905,free space	
Electrical Parameters	Integration Time	8ms-3600s	
	Data Output Interface	USB3.0,RS232,RS485,20pin connector	
	ADC Bit Depth	16-bit	
	Power Supply	5V	
	Operating Current	<3.5A	
Physical Parameters	Operating Temperature	10 ~40	
	Storage Temperature	-20 ~60	
	Operating Humidity	<90%RH (no condensation)	
	Dimensions	180mm*120mm*50mm	
	Weight	1.2kg	

List of Product Models:

Model	Spectral Range(nm)	Resolution(nm)	Slit(µm)
		6.8	200
SR100Q-G21	200~950	2.2	50
SR100Q-G22	350~1100	1.5	25
		1.0	10
SR100Q-G23	200~775	1.6	50
004000	350~925	1.0	25
SR100Q-G24		0.7	10
SR100Q-G25	532~690(4400cm-1*)*	13cm-1	50
SR100Q-G26	638~800(3200cm-1)*	10cm-1	25
SR100Q-G27	785~1050(3200cm-1)*	11cm-1	50

Note: The*are primarily designed for Raman applications, with the corresponding Raman.

Technical Characteristics:

High quantum efficiency, 92%peak@650nm, 83%@232nm

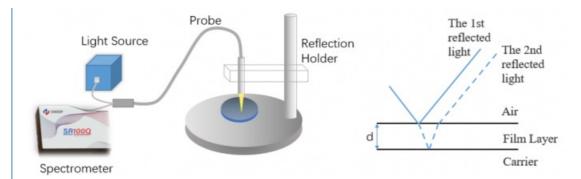
High SNR: Ultra-low dark noise under long integration time, SNR is as high as 1000:1

Noise-free clear processing of weak signal in long exposure, strong adaption to environment

Low-noise and high-speed circuit: USB3.0

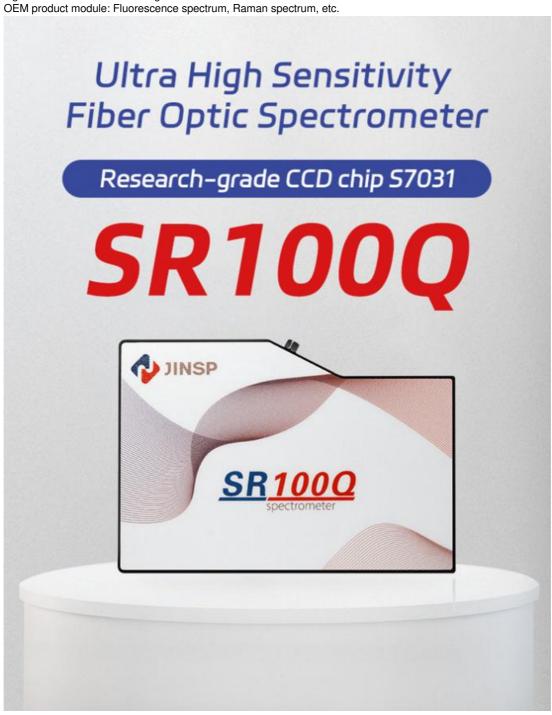
Measurement Method:

A fiber-optic probe directs light toward the film, where it partially reflects at the air-film interface (first beam) and transmits through, reflecting again at the film-substrate boundary (second beam). These two beams interfere due to their path difference, generating an interference spectrum captured by the spectrometer. Thickness (d) is calculated via the extremum method using θ , n, and spectral extrema. Higher thickness increases fringe density, while longer wavelengths reduce it. Proper spectral range and resolution selection are critical for precision.

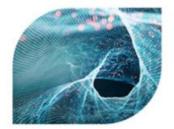


Typical Applications:

Detect absorption, transmittance and reflection Spectrum
Light source and laser wavelength characterization
OFM product module: Fluorescence spectrum, Raman spectrum, etc.



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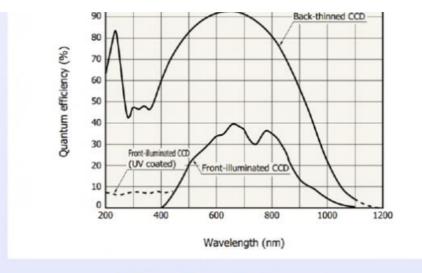


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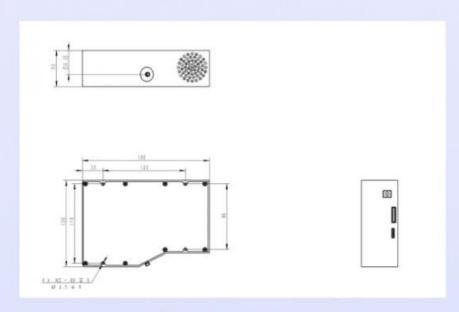


OEM product module: Fluorescence spectrum, Raman spectrum, etc.

(Typ. Ta=25 °C



CCD Quantum Efficiency Curve



Installation dimension drawing

Company Introduction:

JINSP Company Limited, abbreviated as "JINSP", is a professional supplier with over 17 years of experience in spectral detection technology products, including Raman, FT-IR, LIBS technologies, etc. After 17 years of technology accumulation, the company's core key technologies have reached the international leading position at the level, and the cumulative number of patent applications exceeded 200.

In addition to its main headquarters located in the bustling city of Beijing, JINSP has established a fully owned subsidiary manufacturing facility situated in the province of Jiangsu, China.

JINSP Company received ISO9001:2015, ISO14001:2015, and ISO45001:2018 certifications. JINSP can provide required certifications, such as certification by the Ministry of Public Security or National Institute of Metrology, Environmental Level Certification, IP Level Certification, CE Certification, Transport Identification Report, EU ECAC certification, German ICT Security Testing, etc.

Company Profile









Exhibition









Certifications







FAQ

A1:We will send you manual and guide vedio in English, it can teach you how to operate the spectrometer. Also our technicians will offer professional tecnical opearation meetings.

Q2: Can your offer a operation traning?

A2: Your technicians can come to our factory for a training. Jinsp engineers can go to your place for local support (installation, training, debugging, maintenance).

Q3: What's your website?

A3:You can visit:www.jinsptech.com

Q4: What about your quality assurance?

A4: We have a quality inspection team. All goods will go through quality inspection before shipment. We can send you pictures for inspection.



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